

# Proton Testing of Micro Advanced Stellar Compass TEC-QCA Support Activity to PROBA-II

Presentation by

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# PROBA-II

## Spacecraft technology miniaturisation

- Attitude measurement sensors
- Attitude control systems
- Integrated data handling
- Enhanced payload and others

Miniature: Micro Advanced Stellar Compass

# Micro Advanced Stellar Compass

- The micro-Advanced Stellar Compass ( $\mu$ ASC) is a highly advanced and fully autonomous star tracker designed to connect 4 camera heads, developed and produced by the Measurement and Instrumentation Systems (MIS) Section of the *Ørsted Department* at the Technical University of Denmark (DTU).
- The  $\mu$ ASC attitude sensor delivers in real-time up to 32 real time attitudes per second a three-axes attitude of its reference frame with respect to the J2000 inertial reference frame at any user specified epoch.
- The data delivered by the  $\mu$ ASC can directly be used to control the attitude of the satellite.

## Test Facilities

- The SEU tests were performed at the Paul Scherrer Institute 14-15 February 2006 by the Space Instrumentation Group at Ørsted•DTU, Denmark with participation from ESA/ESTEC
- The **Danish National Space Center** would like to thank ESA for the economic support and kind assistance (and time) from Dr. Reno Harboe Sørensen and Dr. Frederic Teston from ESA.

## COTS: ASC and $\mu$ ASC

- **C**ompatibility with design
  - **O**bservation
  - **T**ime
  - **S**tudy
- 
- **T**otal dose tests
  - **I**rradiation with particles
  - **D**amage investigation

# Latch-Up Protection

- Several latch-up protection circuits for groups of components operating together
- Increased current consumption mean shut-down and reboot of the entire system to prevent destruction.
- Latch-up protection circuits proved their efficiency with success during heavy ion tests.

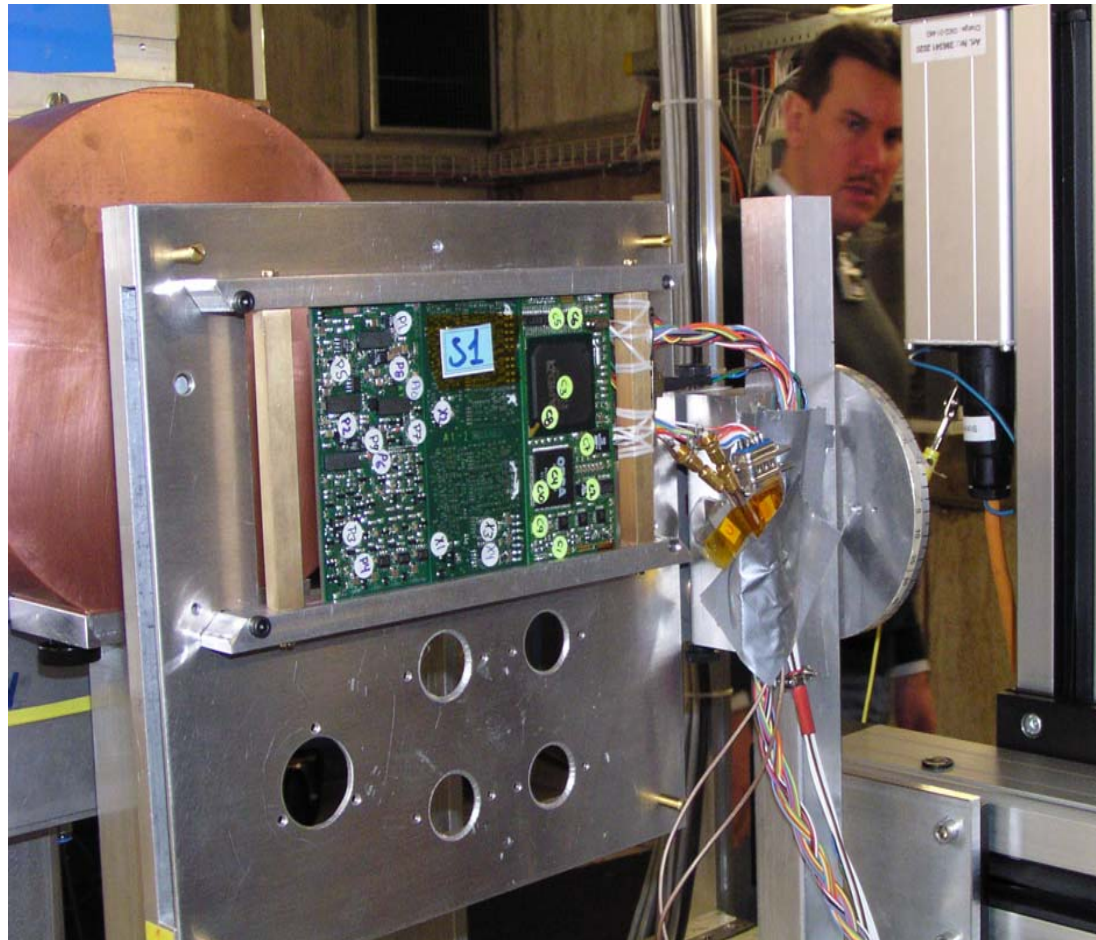
## Correction Mechanisms

- EEC protection on FLASH RAM and SDRAMs
- 2 bits detection, 1 bit correction is used
- Double bit flips means system reboot
- SEUs as bit flips are logged during tests together with the bit addresses

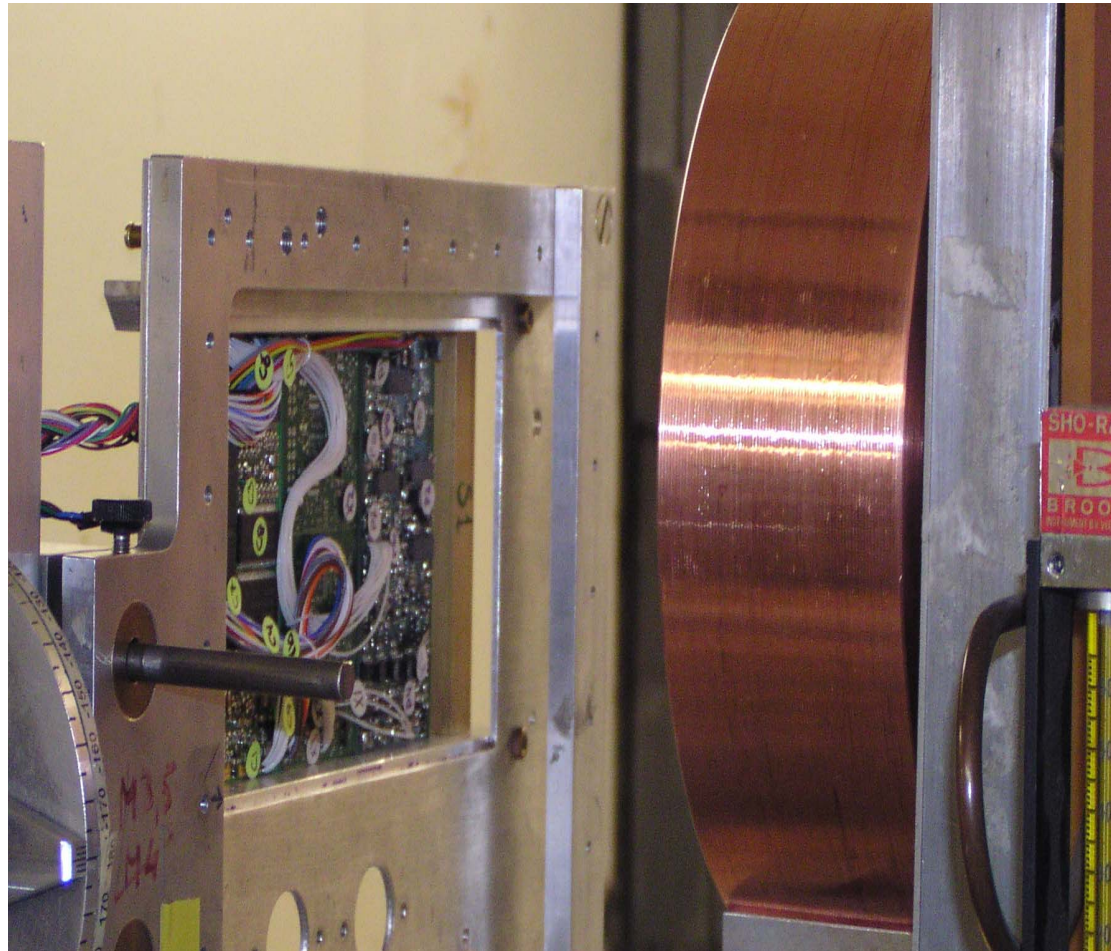
# System Functionality

- All components on board
- Size of test board
- Unintentional irradiation
- Current consumption & System response
- Cross sections
- Irradiation sequence
- Test board set-up
- Proton energy
- Versus single component response
- Selected components

## Layout: Board Size and Set-Up



# Collimator - and Unintentional Irradiation



## Beam Parameters for PSI tests

- 15mm planar beam
- Mean flux  $7.2 \text{ E}^7 \text{ /cm}^2\text{/s}$
- Mean fluence  $9.3 \text{ E}^9 \text{ /cm}^2$
- Mean dose 500 rad(Si)
- Proton energy 223 MeV (32 MeV)
- HY57V651620BLTC-10S: 38, 50, 72, 101, 151  
210 and 223 MeV

# Components w\ Special EGSE Test Programs

|                     |                       |                       |
|---------------------|-----------------------|-----------------------|
| OR2T06A5T144        | Lattice Semiconductor | FPGA                  |
| ELANSC520-100       | AMD                   | CPU                   |
| HY57V651620BLTC-10S | Hynix / Hyundai       | 64 Mbit SDRAM         |
| AT49BV1614T-11TI    | ATMEL                 | FLASH                 |
| AT27C512R           | ATMEL                 | 64K * 8 OTP EPROM     |
| MAX1081AEUP         | MAXIM                 | 8 chn. 10 bit ADC     |
| MAX1444EHJ          | MAXIM                 | 10 bit ADC            |
| MAX3031EESE         | MAXIM                 | Quad Line Driver      |
| MAX3096ESE          | MAXIM                 | Quad Line Receiver    |
| LT1242IS8           | Linear Technology     | Pulse Width Modulator |

## Star Tracking Using 9-Star-Stimulator

- Stimulator update mode
  - House keeping frequency 1 Hz
  - Bitwash frequency 1/min
  - Debug to trap RAM bitflips
  - Exception handling logging
  - Watchdog timeout 2s for rapid recovery
- 
- LT1242IS8, ELANSC520-100, MAX1081AEUP, HY57V651620BLTC-10S

# Star Tracking Using 9-Star-Stimulator

## Monitoring Image Statistics

- Stimulator update mode
- House keeping frequency 1 Hz
- Bitwash frequency 1/min
- Debug to trap RAM bitflips
- Exception handling logging
- Watchdog timeout 2s for rapid recovery
- Debug variance flag for monitoring statistics
- OR2T06A5T144, MAX1444EHJ

## Power Cycling the Instrument

- Reboot continuously
  - Reading from PROM (bootstrap and safe-mode software)
  - Reading from Flash (application mode software)
  - Attitude packet transmission leads to reboot
  - Exception handling logging
  - Final reboot after end of irradiation
- 
- AT49BV1614T-11TI, AT27C512R

## Verifying Telemetry Quality

- Special program for test of line driver
- Memory dump
- Performance evaluation based on checksum errors
- Very low telemetry packet size for better statistics (100 bytes)
- No attitude determination: Stand-by mode
- Exception handling logging
- Watchdog timeout 2s for rapid recovery
- MAX3031EESE

## Verifying Telecommand Quality

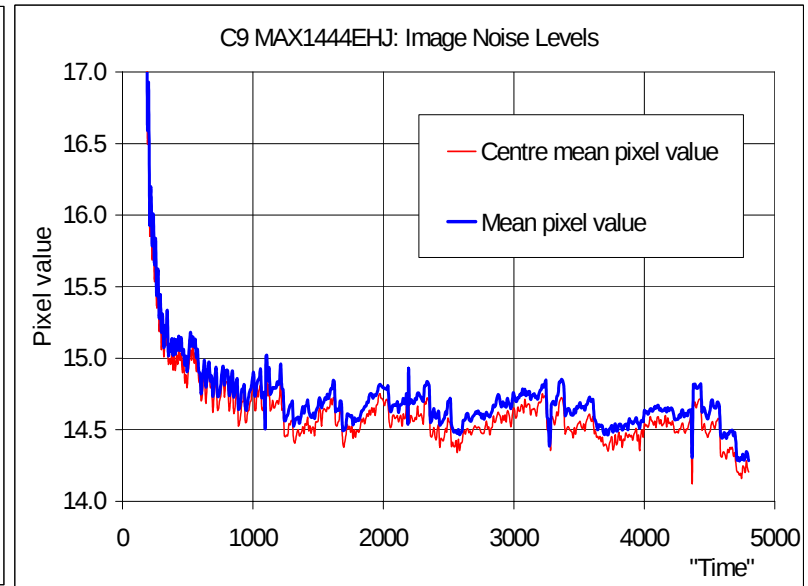
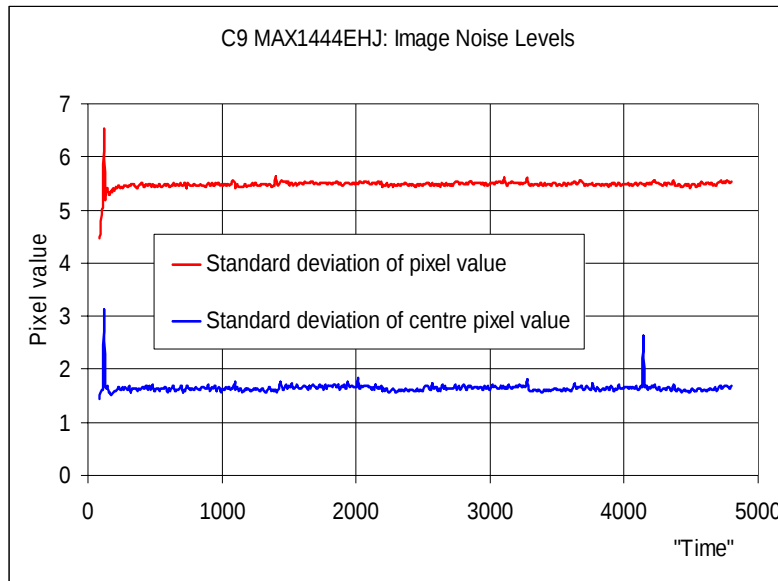
- Special program for test of line receiver
- Continuous House keeping requests at 0.1 Hz
- Performance evaluation based on checksum errors
- No attitude determination: Stand-by mode
- Exception handling logging
- Watchdog timeout 2s for rapid recovery
- MAX3096ESE

## MAX3031EESE

## MAX3096ESE

- MAX3031 generates the 422 signal levels for the telemetry transmission. The telemetry port was sending continuously during the test, i.e. with a duty cycle of 100% while the debug duty cycle was 5%. No component transmission errors on either of the ports were observed during the test.
- MAX3096 transforms the 422 signal levels for the telecommand interface to low voltage signals. No errors were seen for TC-commands during the test of the MAX3096EESE. However, the test caused a reboot and a high number of SEUs was observed because 1/3 of the area of an adjacent SDRAM was irradiated, too.

# MAX1444EHJ and OR2T06A5T144



- No critical signatures in the standard deviation measurements were observed. Slight increase in gain values (AGC level).
- The MAX1444EHJ showed a one-time occurrence of a single minor spike in the centre image (100 by 100 pixels) standard deviation. The spike corresponds to a transient image hotspot .

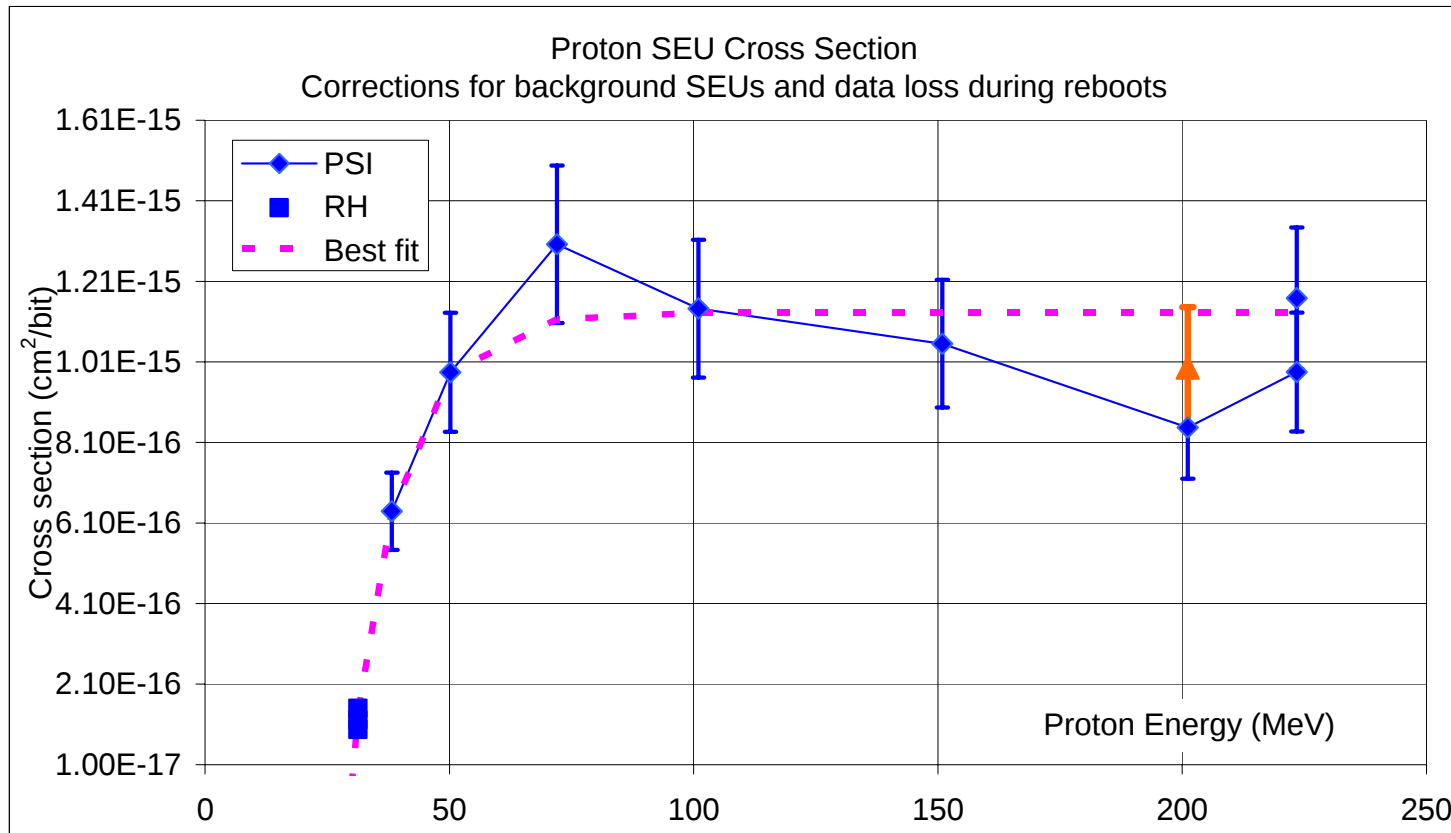
# HY57V651620BLTC-10S: SEUs & Exceptions

|      |    |    |     |     |     |     |         |
|------|----|----|-----|-----|-----|-----|---------|
| MeV  | 38 | 50 | 72  | 101 | 151 | 210 | 223     |
| SEUs | 44 | 74 | 129 | 189 | 435 | 521 | 525/606 |

- 0D General Protection Error
- 02 Double Bit Flip
- 10 Floating Point Error

|      |    |    |      |      |      |      |        |
|------|----|----|------|------|------|------|--------|
| MeV  | 38 | 50 | 72   | 101  | 151  | 210  | 223    |
| Exc. | 0  | 0  | 1 0D | 1 10 | 2 02 | 1 02 | 7/6 02 |

# HY57V651620BLTC-10S: Cross Sections



## Cross Sections: SDRAM and CPU

- CPU  $< 3.3 \text{ E}^{-10} \text{ cm}^2/\text{device}$
- Reboots observed during test due to exceptions  
0D general protection error concerning RAM  
read/write procedures
- SDRAM  $< 4 \text{ E}^{-8} \text{ cm}^2/\text{device}$
- SDRAM  $< 1.5 \text{ E}^{-15} \text{ cm}^2/\text{bit}$

# Occasional SEUs (from SDRAM) Otherwise no effect

- LS1242IS8

Tested twice

1 reboot

- MAX1081AEUP

No latch-ups

No reboots

- AT27C512R

- AT49BV1614T-11TI

Tested together

No reboot problems  
encountered



# Thank You



**Danish Team with ESA/ESTEC**